

# NUF4401MN

## 4 Line EMI Filter with ESD Protection

NUF4401MN is a 4 line EMI filter array for wireless applications. It offers greater than -35 dB attenuation at frequencies from 900 MHz to 2.4 GHz. This device also offers ESD protection—clamping transients from static discharges and ESD protection is provided across all capacitors.

### Features

- Provides EMI Filtering and ESD Protection
- Integration of 20 Discretes
- Compliance with IEC61000-4-2 (Level 4)
  - 10 kV (Contact)
  - 15 kV (Air)
- DFN8, 2x2 mm Package
- Moisture Sensitivity Level 1
- ESD Ratings: Machine Model = C  
Human Body Model = 3B
- This is a Pb-Free Device\*

### Benefits

- Reduces EMI/RFI Emissions on a Data Line
- Integrated Solution Offers Cost and Space Savings
- Reduces Parasitic Inductances Which Offer a More “Ideal” Low Pass Filter Response
- Integrated Solution Improves System Reliability

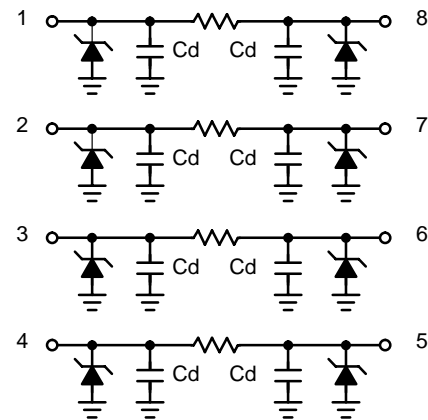
### Applications

- EMI Filtering and ESD Protection on a Data Line
- Wireless Phones
- Handheld Products
- Notebook Computers
- LCD Displays

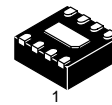


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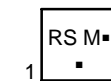


(Top View)

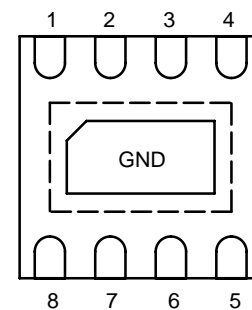


**DFN8  
CASE 506AQ  
PLASTIC**

### MARKING DIAGRAM



RS = Specific Device Code  
M = Month Code  
▪ = Pb-Free Package  
(Note: Microdot may be in either location)



(Bottom View)

### ORDERING INFORMATION

Device	Package	Shipping†
NUF4401MNT1G	DFN8 (Pb-Free)	3000 / Tape & Reel

\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

# NUF4401MN

## MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
ESD Discharge IEC61000-4-2 Contact Discharge	$V_{PP}$	100	kV
Steady-State Power per Resistor	$P_R$	100	mW
Steady-State Power per Package	$P_T$	400	mW
Operating Temperature Range	$T_{OP}$	-40 to 85	°C
Storage Temperature Range	$T_{stg}$	-55 to 150	°C
Maximum Lead Temperature for Soldering Purposes (1.8 in from case for 10 s)	$T_L$	260	°C

Maximum ratings are those values beyond which device damage can occur. Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If these limits are exceeded, device functional operation is not implied, damage may occur and reliability may be affected.

## ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ\text{C}$ unless otherwise noted)

Parameter	Test Conditions	Symbol	Min	Typ	Max	Unit
Maximum Reverse Working Voltage		$V_{RWM}$			5.0	V
Breakdown Voltage	$I_R = 1.0 \text{ mA}$	$V_{BR}$	6.0	7.0	8.0	V
Leakage Current	$V_{RWM} = 3.3 \text{ V}$	$I_R$			100	nA
Resistance	$I_R = 20 \text{ mA}$	$R_A$	170	200	230	$\Omega$
Capacitance (Note 1, 3)	$V_R = 2.5 \text{ V}$ , $f = 1.0 \text{ MHz}$	$C_d$	12	15	18	pF
Cut-Off Frequency (Note 2)	Above this frequency, appreciable attenuation occurs	$f_{3dB}$		125		MHz

1. Measured at  $25^\circ\text{C}$ .
2.  $50 \Omega$  source and  $50 \Omega$  load termination.
3. Total line capacitance is 2 times the diode capacitance ( $C_d$ ).

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## TYPICAL PERFORMANCE CURVES

( $T_A = 25^\circ\text{C}$  unless otherwise specified)

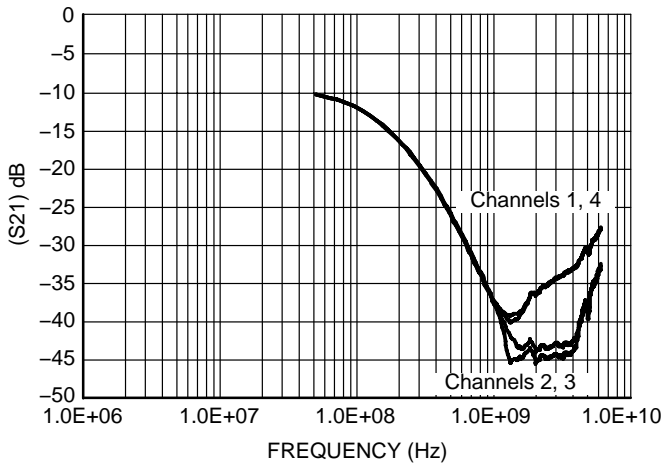


Figure 1. Insertion Loss Characteristics

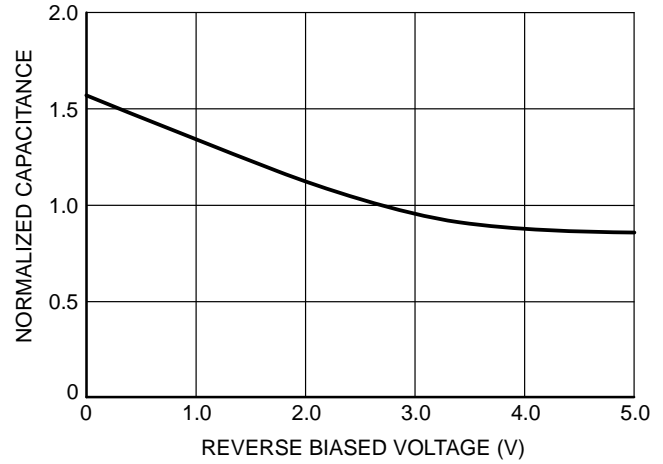


Figure 2. Typical Line Capacitance vs. Reverse Bias Voltage (Normalized to Capacitance @ 2.5 V)

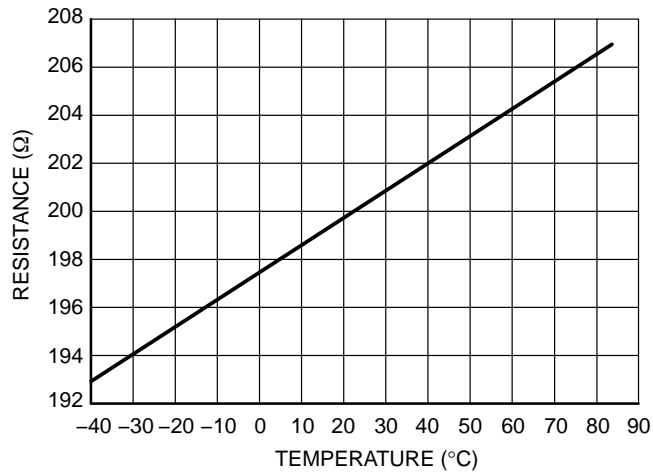


Figure 3. Typical Resistance vs. Temperature

